Test report No. Page

: 29JE0146-HO-01-A

Issued date FCC ID : 1 of 13 : June 17, 2009

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: WAZX1T540SKE11A03

EMI TEST REPORT

Test Report No.: 29JE0146-HO-01-A

Applicant

Mitsubishi Electric Corporation Himeji Works

Type of Equipment

SMART KEYLESS SYSTEM (Receiver)

Model No.

SKE11A-03 (X1T540 VARIANT)

FCC ID

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:

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WAZX1T540SKE11A03

Test regulation

:

FCC Part 15 Subpart B 2009

Test Result

:

Complied

- 1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
- 2. The results in this report apply only to the sample tested.
- 3. This sample tested is in compliance with the above regulation.
- 4. The test results in this report are traceable to the national or international standards.
- 5. This test report must not be used by the customer product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.

Date of test:

June 5, 2009

Tested by:

Takayuki Shimada EMC Services

Approved by:

Makoto Kosaka EMC Services



NVLAP LAB CODE: 200572-0

This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation.

*As for the range of Accreditation in NVLAP, you may refer to the WEB address,

http://uljapan.co.jp/emc/nvlap.html

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SECTION 1: Customer information

Company Name : Mitsubishi Electric Corporation Himeji Works

Address : 840 CHIYODA-MACHI HIMEJI HYOGO 670-8677, JAPAN

Telephone Number : +81-79-298-8994
Facsimile Number : +81-79-298-9929
Contact Person : Yoshiharu Goto

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : SMART KEYLESS SYSTEM (Receiver) Model No. : SKE11A-03 (X1T540 VARIANT)

Serial No. : 20090604-R1
Receipt Date of Sample : June 5, 2009
Country of Mass production : June 1

Country of Mass-production : Japan

Condition of EUT : Production prototype

(Not for Sale: This sample is equivalent to mass-produced items.)

Modification of EUT : No Modification by the test lab

2.2 Product Description

Model No: SKE11A-03 (X1T540 VARIANT) (referred to as the EUT in this report) is the SMART KEYLESS SYSTEM (Receiver). Original receiver (Model No: SKE11A-03) was tested before. This model is X1T540 VARIANT of original model.

Clock frequency(ies) in the system : 29.509394MHz Equipment Type : Receiver

Type of Receiver : Super Heterodyne

Frequency of Operation : 315MHz
Intermediate Frequency : 233kHz
Antenna Type : Bar Antenna

Local Oscillator : $(29.509394 \text{MHz} / 3) \times 32 = 314.767 \text{MHz} \text{ (Local Oscillator Frequency)}$

Method of Frequency Generation : Crystal Operating voltage : DC 5.0V

FCC15.111(b)

The receiving antenna (of this EUT) is installed in the place where the end users cannot remove it.

Therefore, Radiated emission test was performed.

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SECTION 3: Test specification, procedures & results

3.1 Test specification

Test Specification : FCC Part 15 Subpart B 2009, final revised on February 27, 2009

Title : FCC 47CFR Part15 Radio Frequency Device

Subpart B Unintentional Radiators

3.2 Procedures and results

Item	Test Procedure	Limits	Deviation	Worst margin	Result
Conducted emission	FCC: ANSI C63.4: 2003 7. AC powerline conducted emission measurements IC: RSS-Gen 7.2.2	Receiver	N/A	N/A *1)	N/A
Radiated emission	FCC: ANSI C63.4: 2003 8. Radiated emission measurements IC: RSS-Gen 4.10	Receiver	N/A	19.0dB 944.301MHz Horizontal / Vertical, QP	Complied

^{*}Note: UL Japan, Inc's EMI Work Procedure QPM05.

3.3 Addition to standard

No addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room	Conducted emission				
(semi-	(<u>+</u> dB)				
anechoic	150kHz-30MHz				
chamber)					
No.1	3.7dB				
No.2	3.7dB				
No.3	3.7dB				
No.4	3.7dB				

Test room (semi-	Radiated emission (10m*)(<u>+</u> dB)					Radiated (3m*)(
anechoic	9kHz-	30MHz-	300MHz-	9kHz-	30MHz-	300MHz-	1GHz-	18GHz-	26.5GHz-
chamber)	30MHz	300MHz	1GHz	30MHz	300MHz	1GHz	18GHz	26.5GHz	40GHz
No.1	3.1dB	4.4dB	3.9dB	3.2dB	3.8dB	3.9dB	5.0dB	5.0dB	5.4dB
No.2	-	-	-	3.2dB	4.4dB	4.0dB	5.0dB	5.2dB	5.4dB
No.3	-	-	-	3.2dB	4.2dB	3.8dB	5.0dB	5.3dB	5.3dB
No.4	-	_	-	3.2dB	4.0dB	3.8dB	5.0dB	5.3dB	5.3dB

^{*10}m/3m = Measurement distance

Radiated emission test (3m)

The data listed in this test report has enough margin, more than the site margin.

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^{*1)} The test is not applicable since the EUT is not the device that is designed to be connected to the public utility (AC) power line.

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3.5 Test Location

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	FCC	IC Registration	Width x Depth x	Size of	Other
	Registration Number	Number	Height (m)	reference ground plane (m) / horizontal conducting plane	rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

^{*} Size of vertical conducting plane (for Conducted Emission test): 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Data of EMI, and Test instruments

Refer to APPENDIX 1 to 3.

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SECTION 4: Operation of E.U.T. during testing

4.1 Operating modes

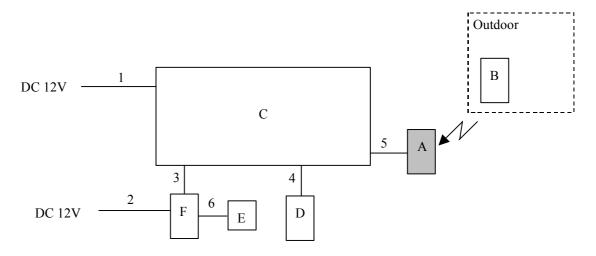
The mode is used : Continuous Receiving mode (315MHz)

*This EUT receives 315MHz signal (FSK modulated) from hand unit.

SMART KEYLESS SYSTEM (Transmitter) was operated manually by a test engineer and

the test was performed with the EUT receiving 315MHz.

4.2 Configuration and peripherals



*Cabling and setup were taken into consideration and test data was taken under worse case conditions.

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Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remark
A	SMART KEYLESS	SKE11A-03	20090604-R1	Mitsubishi Electric	EUT
А	SYSTEM (Receiver)	(X1T540 VARIANT)		Corporation Himeji Works	
В	SMART KEYLESS	SKE11A-03	20090604-T1	Mitsubishi Electric	-
Ь	SYSTEM (Transmitter)			Corporation Himeji Works	
C	SMART KEYLESS	SKE11A-03	20090604-01	Mitsubishi Electric	-
C	SYSTEM (Smart ECU)			Corporation Himeji Works	
D	Antenna A	-	=	Mitsubishi Electric	-
D				Corporation Himeji Works	
E	SKE CHECKER LED	-	=	Mitsubishi Electric	-
L				Corporation Himeji Works	
F	SKE CHECKER	-	=	Mitsubishi Electric	-
Г				Corporation Himeji Works	

List of cables used

No.	Name	Length (m)	Sh	Shield		
			Cable	Connector		
1	DC Cable	1.3	Unshielded	Unshielded	-	
2	DC Cable	1.4	Unshielded	Unshielded	-	
3	Signal Cable	1.4	Unshielded	Unshielded	-	
4	Signal Cable	1.5	Unshielded	Unshielded	-	
5	Signal / DC Cable	1.3	Unshielded	Unshielded	-	
6	Signal Cable	0.15	Unshielded	Unshielded	-	

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SECTION 5: Radiated Emission

5.1 Operating environment

Test place : No.3 semi anechoic chamber

Temperature : See data Humidity : See data

5.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The EUT was set on the edge of the tabletop.

Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength.

Photographs of the set up are shown in Appendix 1.

5.3 Test conditions

Frequency range : 30MHz-300MHz (Biconical antenna) / 300MHz-1000MHz (Logperiodic antenna)

1000MHz-2000MHz (Horn antenna)

Test distance : 3m EUT position : Table top EUT operation mode : See Clause 4.1

5.4 Test procedure

The height of the measuring antenna varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.

The radiated emission measurements were made with the following detector function of the test receiver and the Spectrum analyzer.

Frequency	Below 1GHz	Above 1GHz
Instrument used	Test Receiver	Spectrum Analyzer
IF Bandwidth	QP: BW 120kHz	PK: RBW:1MHz/VBW: 1MHz
		AV *1): RBW:1MHz/VBW:10Hz

^{*1)} When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

- The noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

6.5 Test result

Summary of the test results: Pass

Date: June 5, 2009 Test engineer: Takayuki Shimada

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